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**M.Tech. Degree Examination, December 2010**  
**Design of VLSI System**

Time: 3 hrs.

Max. Marks:100

**Note: Answer any FIVE full questions.**

- 1 a. Explain the structured strategies, used to reduce the complexity of design. (08 Marks)  
 b. Explain the design flow of automated layout generation. (12 Marks)
- 2 a. Compare the different VLSI design methods (Cell based, custom design & FPGA). (07 Marks)  
 b. Explain the programmed behavioral synthesis. (07 Marks)  
 c. What are gray cell and black cell? Explain. (06 Marks)
- 3 a. Explain the valency-4 Manchester carry chain, with a circuit diagram. Give the relevant equations. (10 Marks)  
 b. Explain the carry look ahead adder. Also, draw the group PG network for 16-bit CLA. (10 Marks)
- 4 a. Draw the table for radix 4 modified booth encoding values. Design a booth encoder and a booth selector, using this table. (10 Marks)  
 b. Explain and write the dot diagram for Wallace tree multiplier. (06 Marks)  
 c. Explain the prefix computation, with respect to priority encoder. (04 Marks)
- 5 a. Explain the read and write operation of 6T SRAM cell. (08 Marks)  
 b. Estimate the delays of 8:256 decoders, using static CMOS gates. Assume decoder has an electrical effort of  $H = 10$  and that both complement and true inputs are available. (06 Marks)  
 c. Explain the advantages and disadvantages of NAND ROMs, as compared to NOR ROMs. (06 Marks)
- 6 a. Explain the bi-directional input-output pad circuitry. (06 Marks)  
 b. Define the clock skew, with an example. (04 Marks)  
 c. Give the classification of global clock distribution. Explain the H-trees for global clock distribution. (10 Marks)
- 7 a. Explain the non-recurring engineering costs and recurring costs, in the design economics. (08 Marks)  
 b. Explain the various levels of logic verification. (08 Marks)  
 c. What is a test bench? How is it used to verify the design? (04 Marks)
- 8 a. Explain the following :  
     i) Observability and controllability  
     ii) Stuck-At-0 and Stuck-At-1 (08 Marks)  
 b. How is the pseudo random sequence generator used, in the built-in-self-test design? (06 Marks)  
 c. With a neat diagram, explain the boundary scan architecture. (06 Marks)